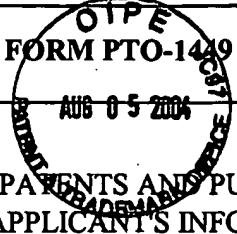


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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT		Applicant: Peter F. Symosek et al.	
		Filing Date: November 20, 2003	Group Art: 2133

### U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
KK	2001/005863 A1	06/2001	Schreier et al.			
KK	5,884,226	03/1999	Anderson et al.			

### FOREIGN PATENT DOCUMENTS

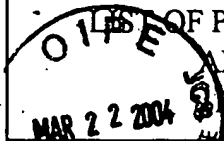
Examiner Initial	Document No.	Date	Country	Translation Yes No
KK	03054824 A	07/2003	WO	

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KK	Griffin et al., "Characterization of gaseous effluents from modeling of LWIR hyperspectral measurements," Proceedings of the SPIE - The International Society for Optical Engineering, vo. 4381, pp. 360-369, 2001.
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KK	Hanaizumi et al., "Simplified method of measuring minor gas constituents from ILAS-II transmittance spectra," Proceedings of the SPIE for Optical Engineering, vol. 4539, pp. 125-133, February 2002.

EXAMINER: /Kibrom Gebresilassie/	DATE CONSIDERED: 01/23/2007
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>FORM PTO-1449</b>		<b>Atty. Docket No.:</b> H0003798(1100.1204101)	<b>Serial No.:</b> 10/718,168
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		<b>Filing Date:</b> November 20, 2003	<b>Group Art:</b> unknown

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KK	5,315,513	05/1994	Abreu et al.			
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KK	Acharya, P.K., et al., "MODTRAN4: Multiple Scattering and Bi-Directional Reflectance Distribution Function (BRDF) Upgrades to MODTRAN, SPIE Proceeding, Optical Spectroscopic Techniques and Instrumentation for Atmospheric and Space Research III, Vol. 3756, 9 pages, July 1999.
KK	Polak, M.L., et al., "Passive Fourier-transform infrared spectroscopy of chemical plumes: an algorithm for quantitative interpretation and real-time background removal," Applied Optics, Vol. 34, No. 24, pp. 5406-5412, August 20, 1995.

<b>EXAMINER:</b> /Kibrom Gebresilassie/	<b>DATE CONSIDERED:</b> 07/10/2006
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